

Article title: Validation of distal radius failure load predictions by homogenized- and micro- Finite Element analyses based on second generation high resolution peripheral quantitative CT images.

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Electronic Supplementary Material 3: Damage plot (hFE) and Von Mises Strain distributions (mFE and hFE) for modelled sections

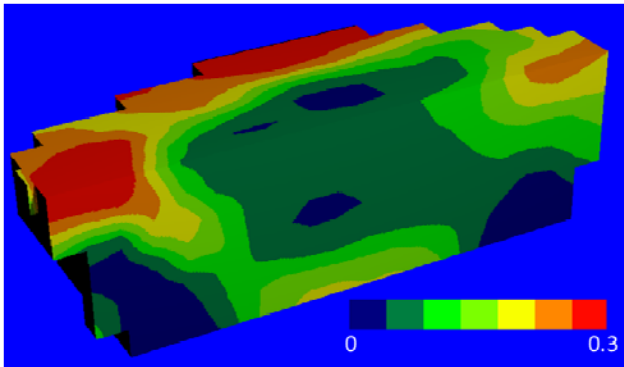


Fig 1. Damage distribution at the failure load for the hFE model of one of the samples just after reaching the failure load. The model is cut in half to reveal the inside strain distribution.

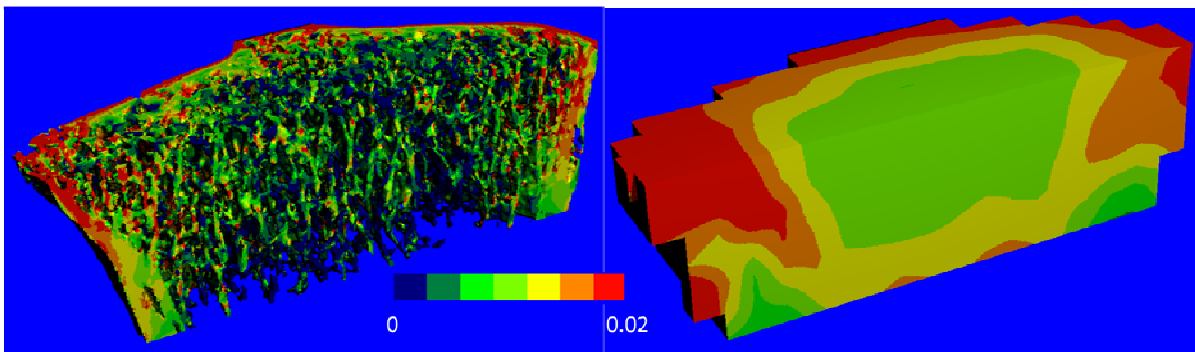


Fig 2. Von Mises strain calculated for the mFE model (left) and the hFE model (right) for one of the samples compressed to a 1% strain. The models are cut in half to reveal the inside strain distribution.